



2. It is hereby certified:

☐ that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Statement, or

☐ that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in § 1.56 (c) more than three months prior to the filing of the Statement.

3. ☐ Consideration of the following additional information (including any co-pending or abandoned U.S. applications, prior uses and/or sales, etc.) is requested:

4. For each non-English language reference listed on the attached Form PTO-1449:

☐ reference is made to an English language translation submitted herewith, and/or

☐ reference is made to a foreign patent office search report (in the English language) submitted herewith, and/or

☐ reference is made to an English language translation of a foreign patent office search report submitted herewith, and/or

☐ reference is made to the concise explanation contained in the specification of the present application at page(s) \_\_\_\_\_, and/or

☐ reference is made to the concise explanation set forth below:

5. ☐ Applicant also offers the following comments for the Examiner's consideration:

6. ☐ Also enclosed is a copy of a foreign search report citing these references.

7. ☐ The listed documents were brought to the attention of the Applicant(s) after payment of the issue fee in the captioned case. The documents were cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement. Applicant(s) request this Information Disclosure Statement and attached Form PTO-1449 be placed in the file of the captioned application.

8. ☐ Applicant(s) requests that the Information Disclosure Statement and attached Form PTO-1449 and references, which are being filed before the grant of the patent and pursuant to 37 C.F.R. § 1.97(i), be placed in the file of the captioned application.

If any required fees are missing, the Commissioner is authorized to charge said fees to Conley, Rose & Tayon, P.C. Deposit Account No. 03-2769/5589-03501.

Respectfully submitted,



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Form PTO-1449 (modified)  
List of Patents and Publications  
For Applicant's Information  
Disclosure Statement  
(Use several sheets if necessary)

ATTY. DKT. NO. 5589-03501

SERIAL NO. 10/616,086

APPLICANT: Miller et al.

GROUP: 2862

FILING DATE: July 9, 2003

## U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	A1	4599558	7/1986	Castellano, Jr. et al.			
	A2	4812756	3/1989	Curtis et al.			
	A3	5485091	1/1996	Verkuil			
	A4	5594247	1/1997	Verkuil et al.			
	A5	5644223	7/1997	Verkuil			
	A6	5650731	7/1997	Fung et al.			
	A7	5767693	6/1998	Verkuil et al.			
	A8	6097196	8/2000	Verkuil et al.			
	A9	6202029	3/2001	Verkuil et al.			

## FOREIGN PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	A10	Numerical Recipes in C, The Art of Scientific Computing, 2nd Ed., © Cambridge University Press 1988, 1992, p. 683.
	A11	Weinberg, "Tunneling of Electrons from Si into Thermally Grown SiO <sub>2</sub> ," Solid-State Electronics, 1977, Vol. 20, pp. 11-18.
	A12	Verkuil, "Rapid Contactless Method for Measuring Fixed Oxide Charge Associated with Silicon Processing," IBM Technical Disclosure Bulletin, Vol. 24, No. 6, 1981, pp. 3048-3053.
	A13	"Contactless Photovoltage vs. Bias Method for Determining Flat-Band Voltage," IBM Technical Disclosure Bulletin, Vol. 32, Vol. 9A, 1990, pp. 14-17.
	A14	"Contactless Electrical Equivalent Oxide Thickness Measurement," IBM Technical Disclosure Bulletin, Vol. 29, No. 10, 1987, pp. 4622-4623.

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.

Information Disclosure Statement--PTO 1449 (modified)